Using eGaN® FETs for Envelope Tracking Buck Converters

Johan Strydom

Efficient Power Conversion Corporation

Agenda

- Overview of Envelope Tracking
- Why eGaN® FETs for Envelope Tracking
- Maximizing Device Performance
- Experimental Results
- Current Limitations
- Summary
- Q & A

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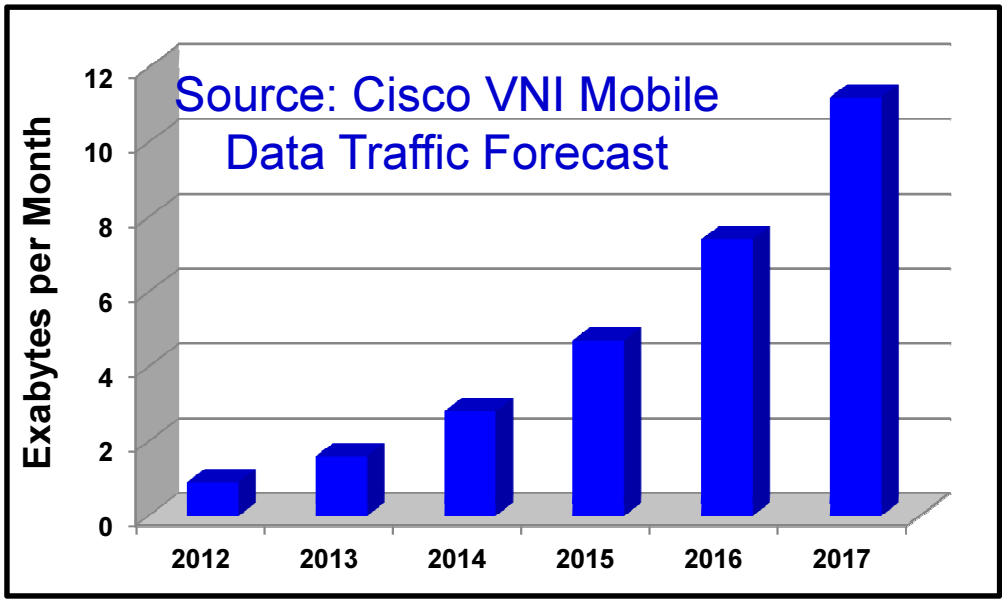
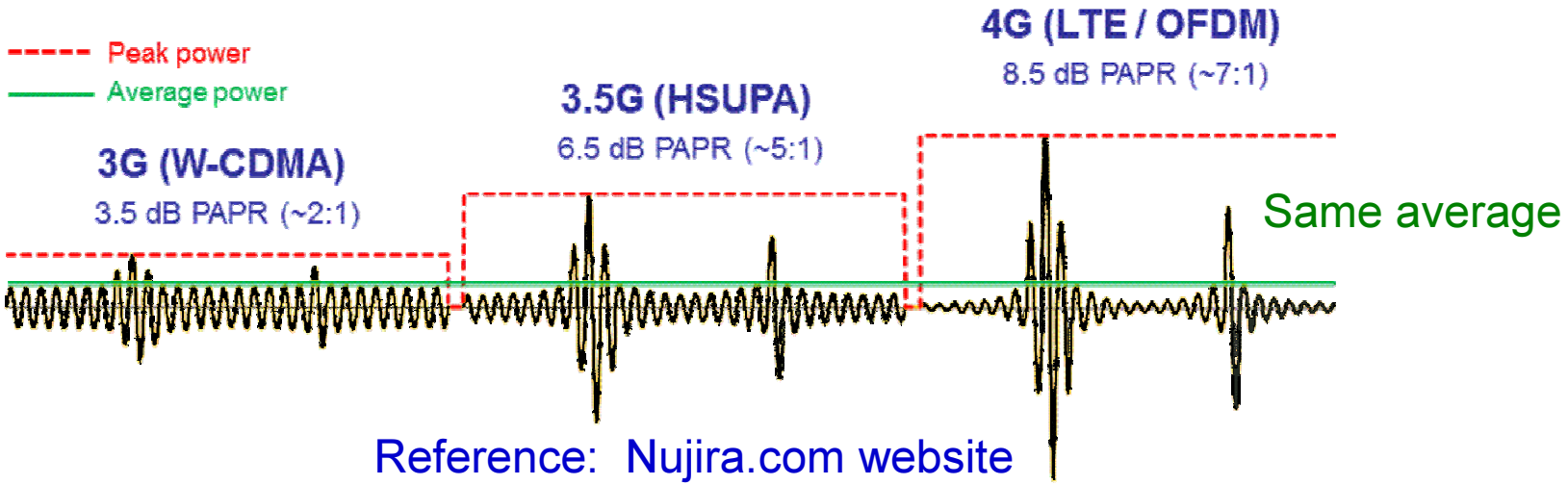
Overview of Envelope Tracking

Why Envelope Tracking?

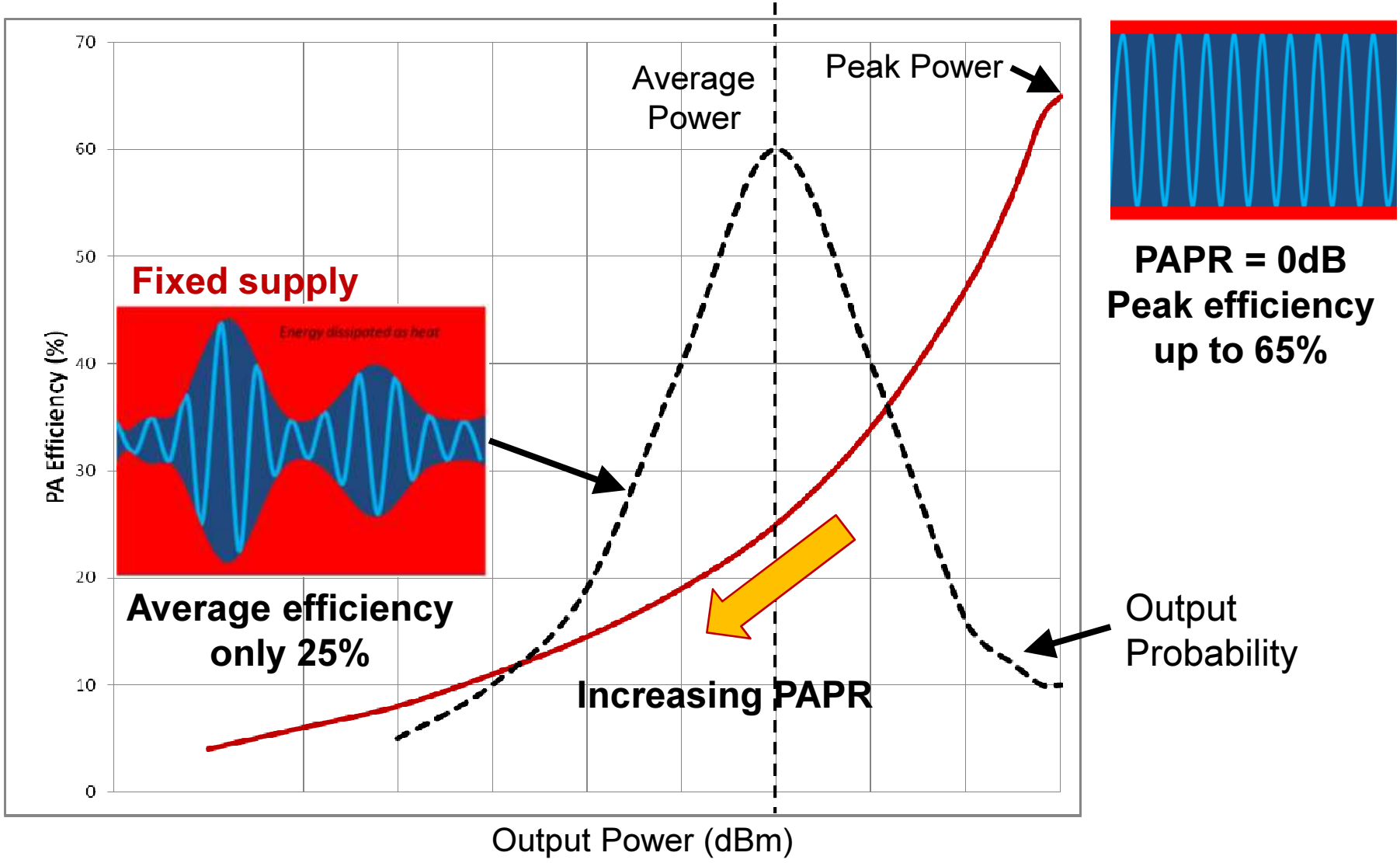


66% Compound annual growth rate (CAGR)



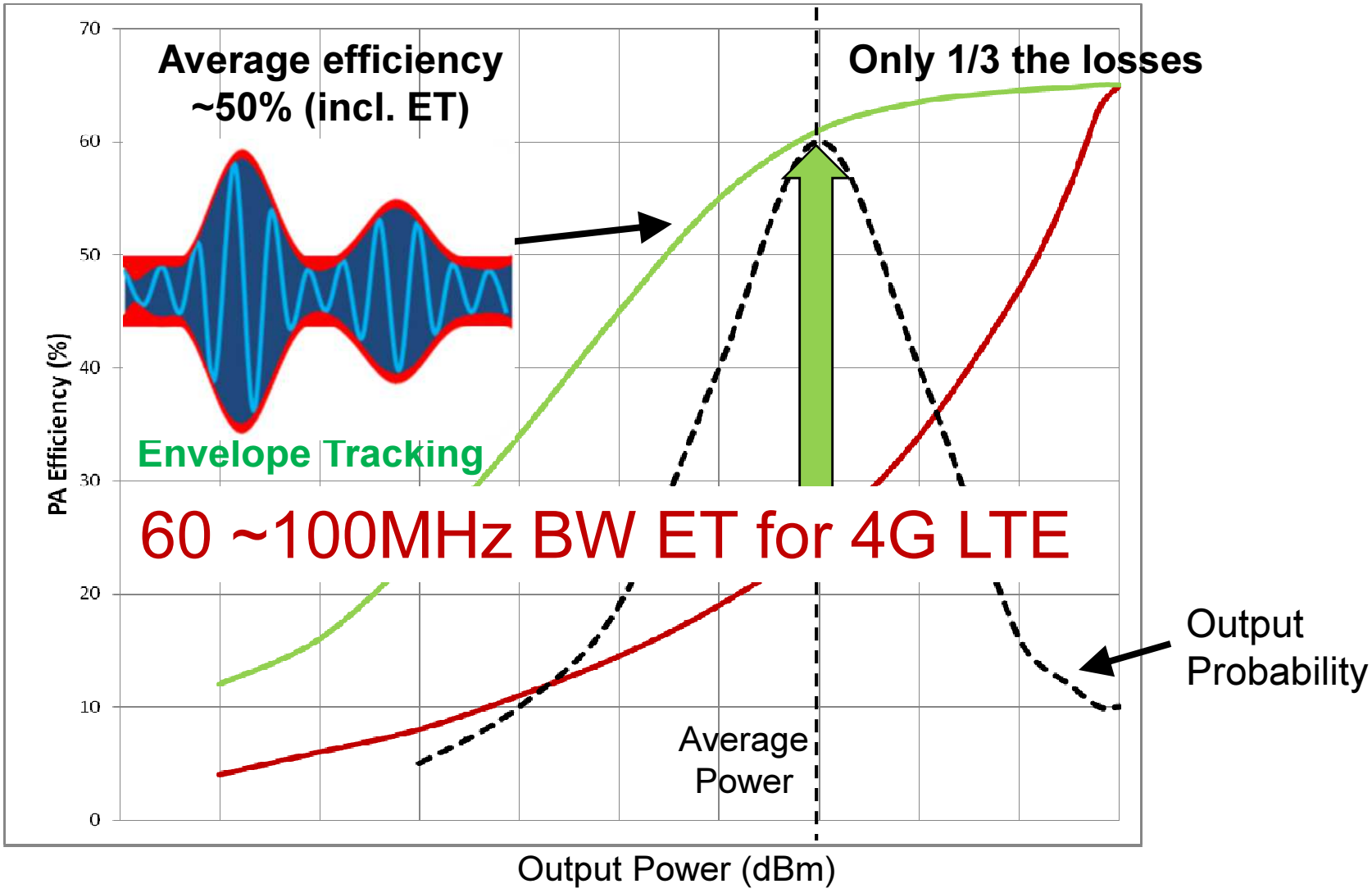
Reference: Nujira.com website

Effect of PAPR

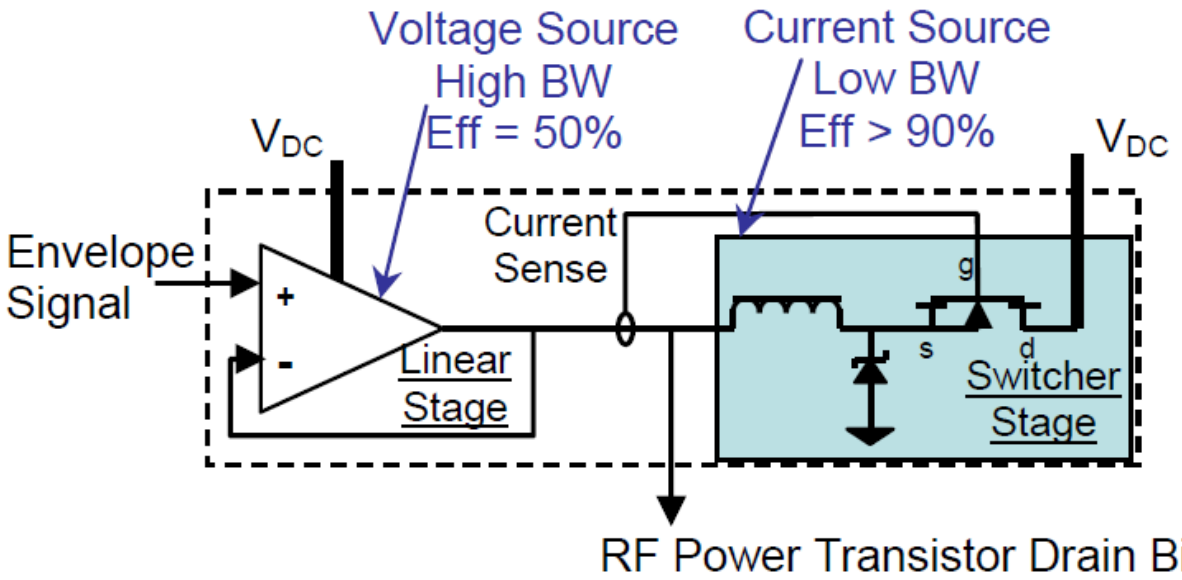


PAPR = 0dB
Peak efficiency up to 65%

Effect of Envelope Tracking



Hybrid ET Implementation



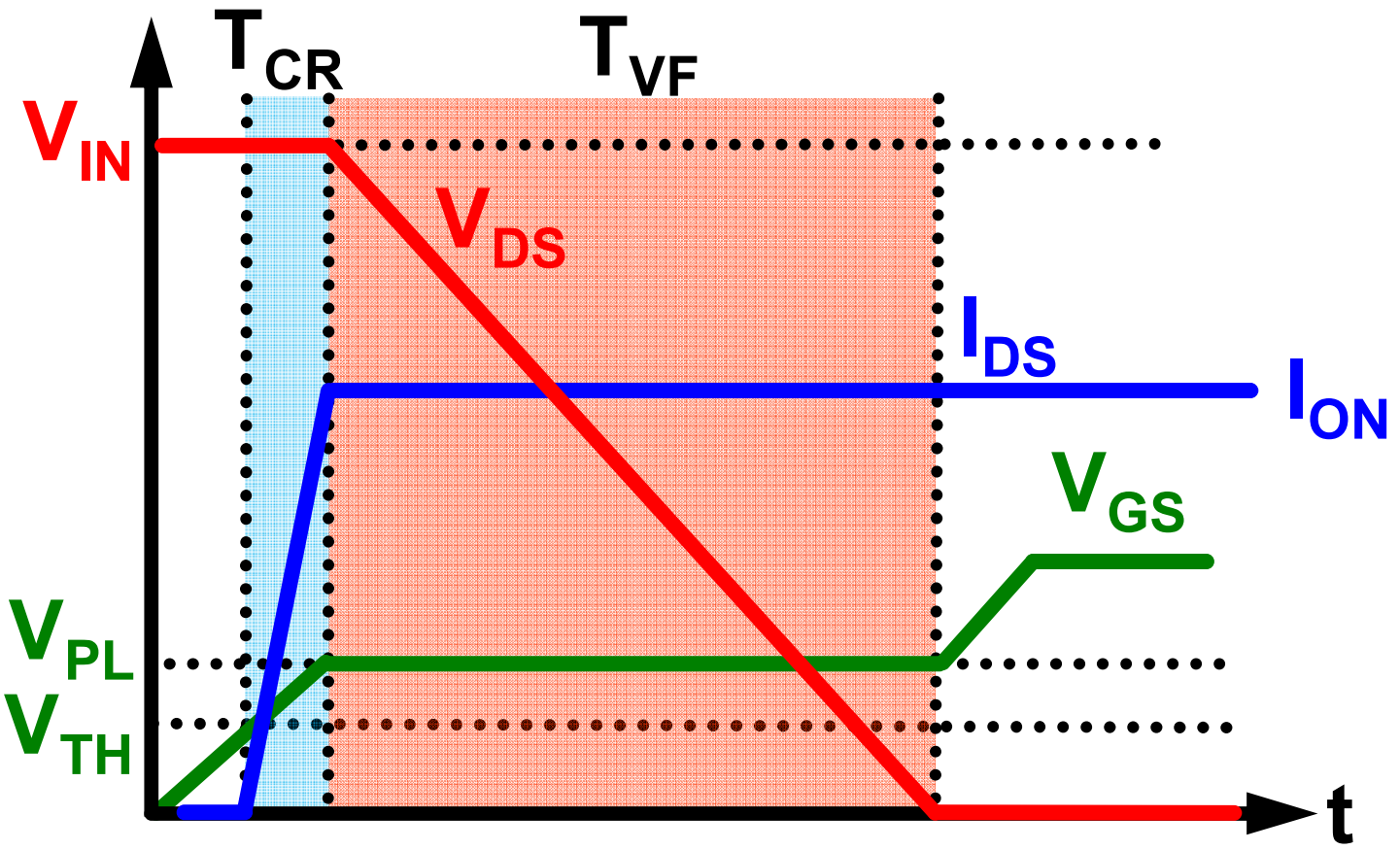
Improvement in switching device performance buys:

- Improves overall ET efficiency
- Increases Switcher stage bandwidth
- Simplifies Linear stage design / Removes it entirely?
- Increase system BW which increases RFPA fidelity

Kimball, Don, et al. "50% PAE WCDMA basestation amplifier implemented with GaN HFETs." *Compound Semiconductor Integrated Circuit Symposium, 2005. CSIC'05. IEEE*. IEEE, 2005.

Why eGaN FETs for Envelope Tracking

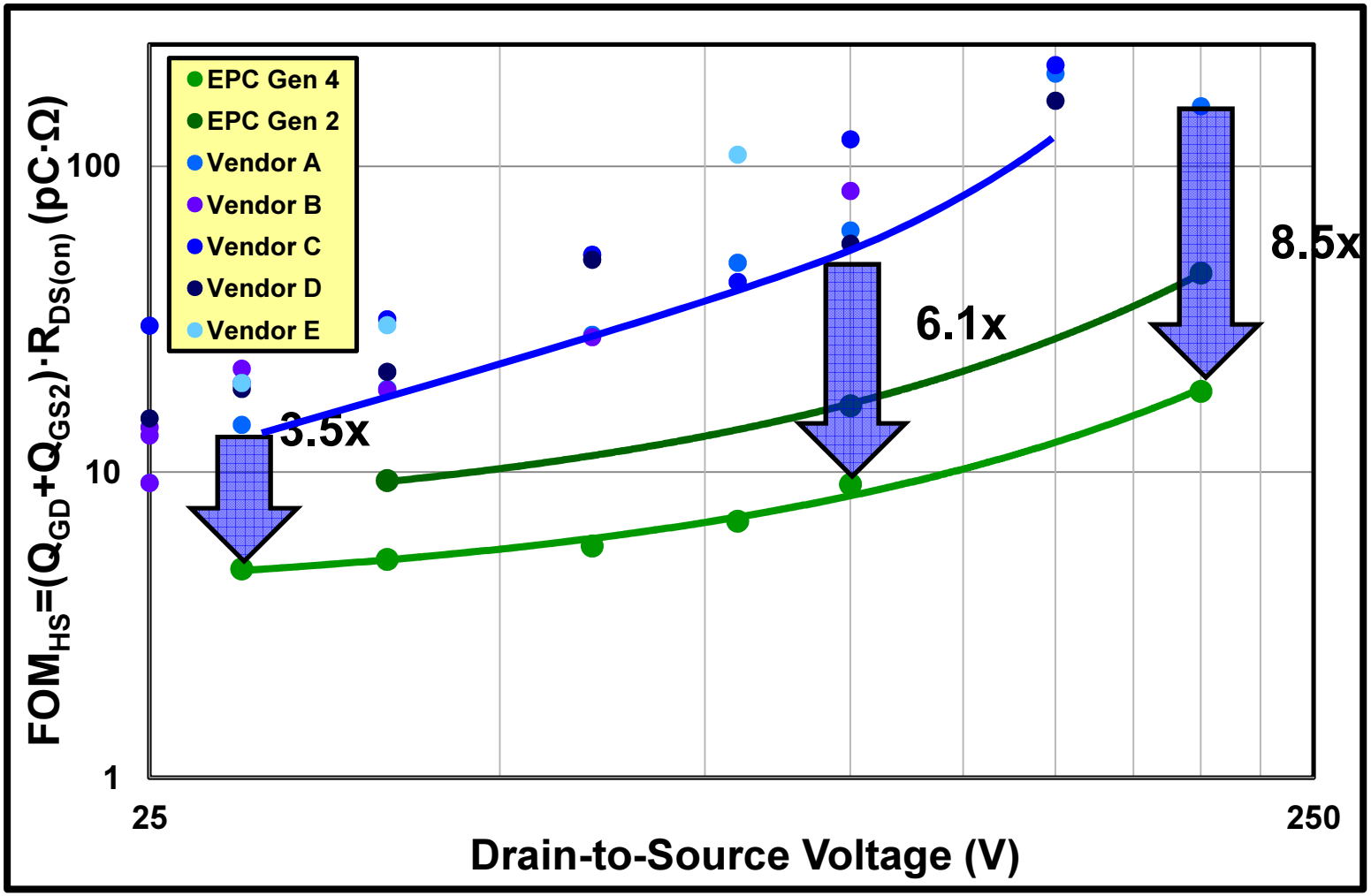
Idealized Switching



$$P_{T_{CR}} \alpha \frac{V_{IN} * I_{ON} * Q_{GS2}}{2 * I_G}$$

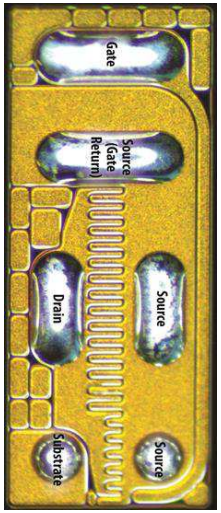
$$P_{T_{VF}} \alpha \frac{V_{IN} * I_{ON} * Q_{GD}}{2 * I_G}$$

Hard-Switching Figure of Merit



V_{DS}=0.5·V_{DSS}, I_{DS}=20 A

High Frequency eGaN FETs



EPC Part No.	BV (V)	Max. $R_{DS(ON)}$ (mΩ) (V_{GS} = 5V, I_D = 0.5 A)	Min. Peak Id (A) (Pulsed, 25 °C, T_{pulse} = 300 µs)	Typical Charge (pC)					Typical Capacitance (pF) (V_{DS} = 20 V; V_{GS} = 0 V)		
				Q_G	Q_{GD}	Q_{GS}	Q_{OSS}	Q_{RR}	C_{ISS}	C_{OSS}	C_{RSS}
EPC8004	40	125	7.5	358	31	110	493	0	45	17	0.4
EPC8007	40	160	6	302	25	97	406	0	39	14	0.3
EPC8008	40	325	2.9	177	12	67	211	0	25	8	0.2
EPC8009	65	138	7.5	380	36	116	769	0	47	17	0.4
EPC8005	65	275	3.8	218	18	77	414	0	29	9.7	0.2
EPC8002	65	530	2	141	9.4	59	244	0	21	5.9	0.1
EPC8003	100	300	5	315	34	110	1100	0	38	18	0.2
EPC8010	100	160	7.5	354	32	109	1509	0	47	18	0.2

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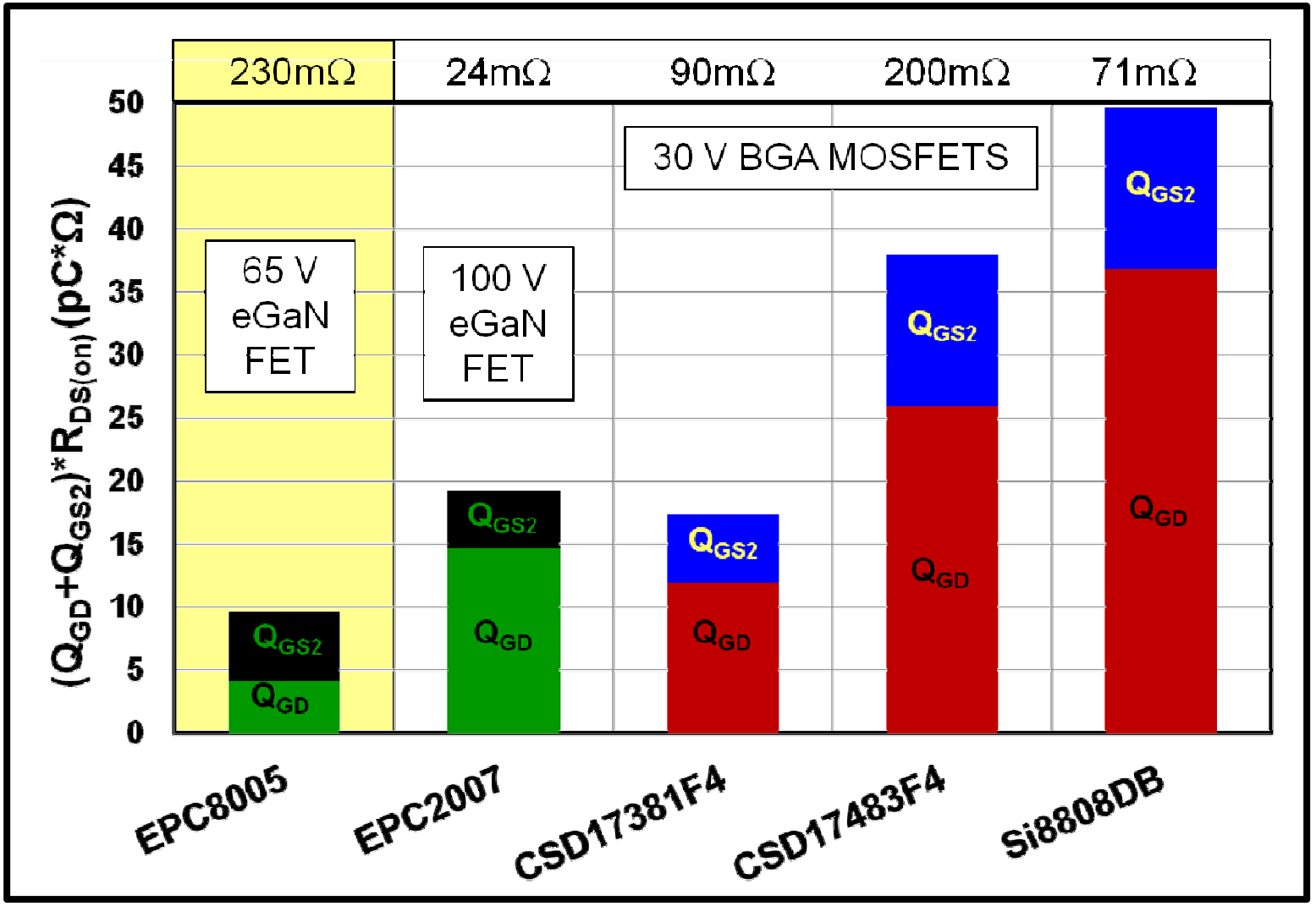
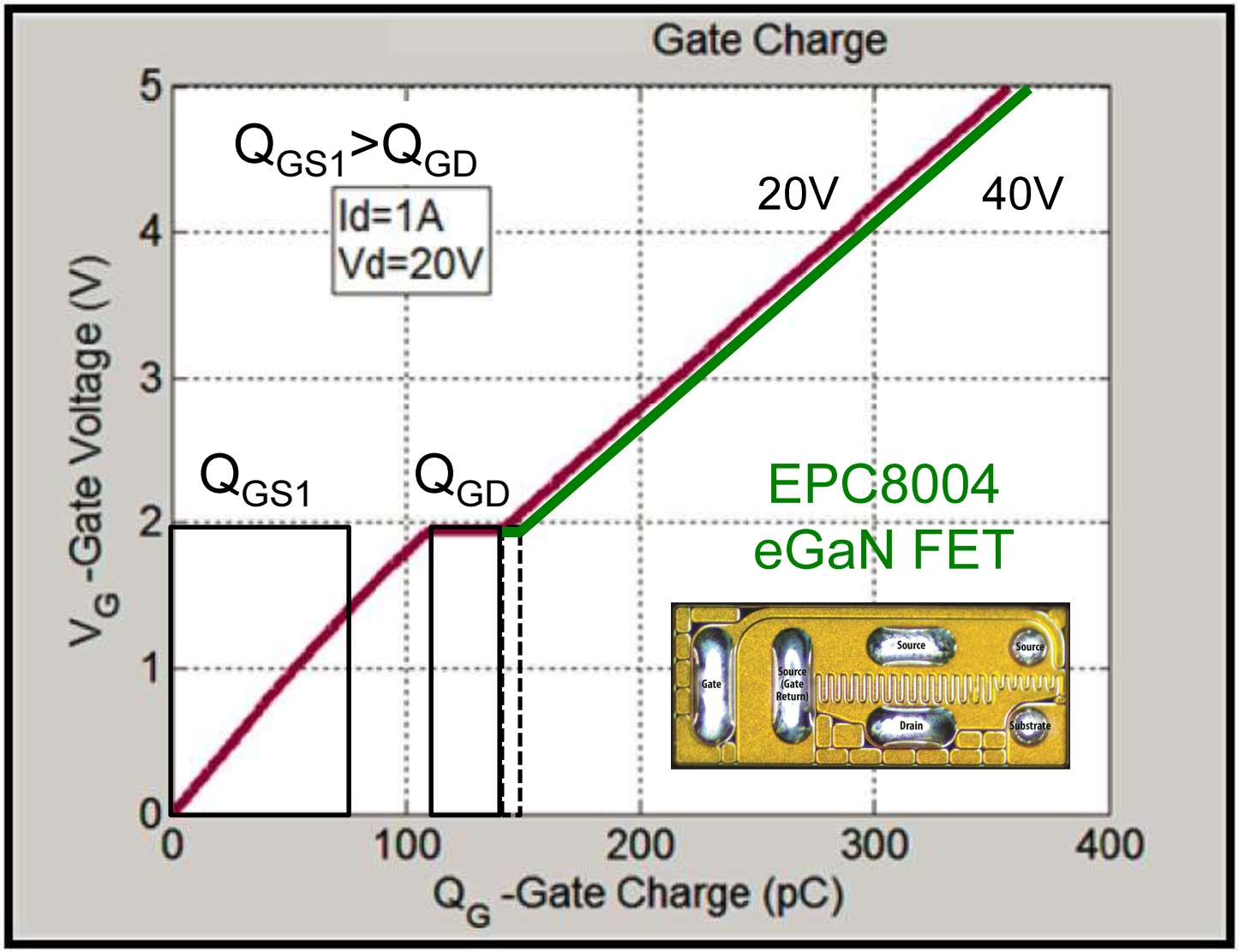
Hard Switching FOM

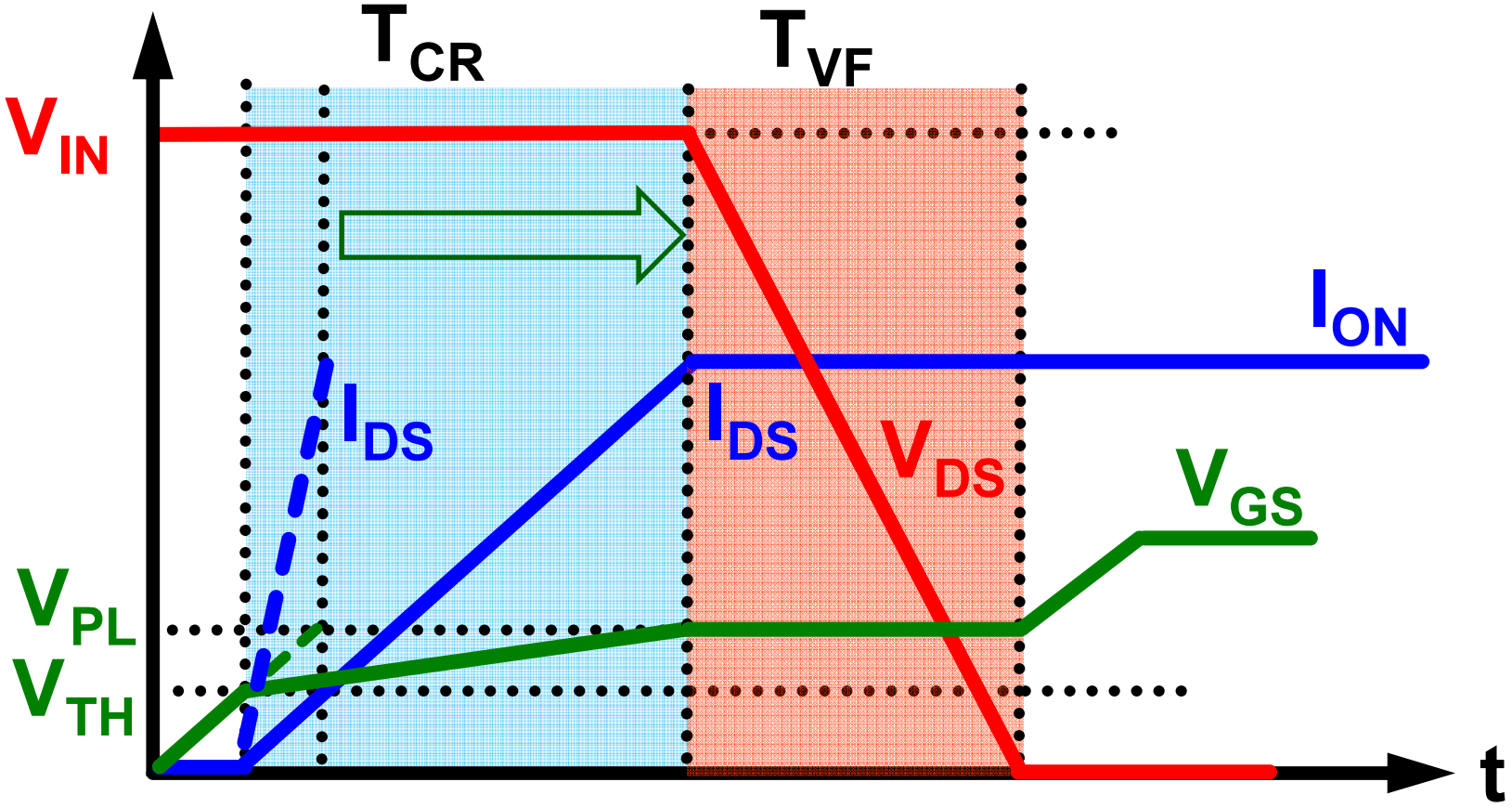


dv/dt Turn-on Immunity



Maximizing Device Performance

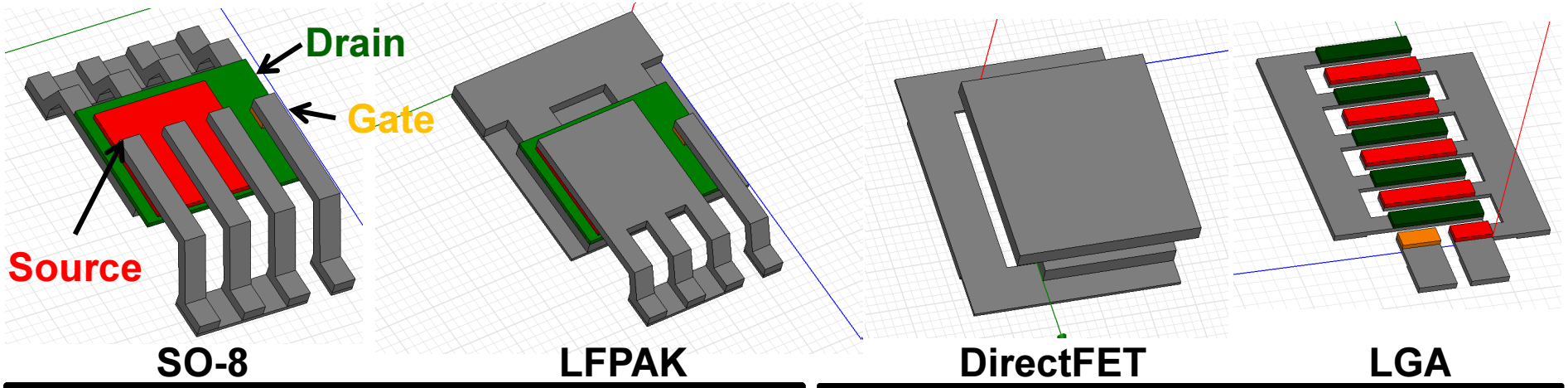
Common Source Inductance

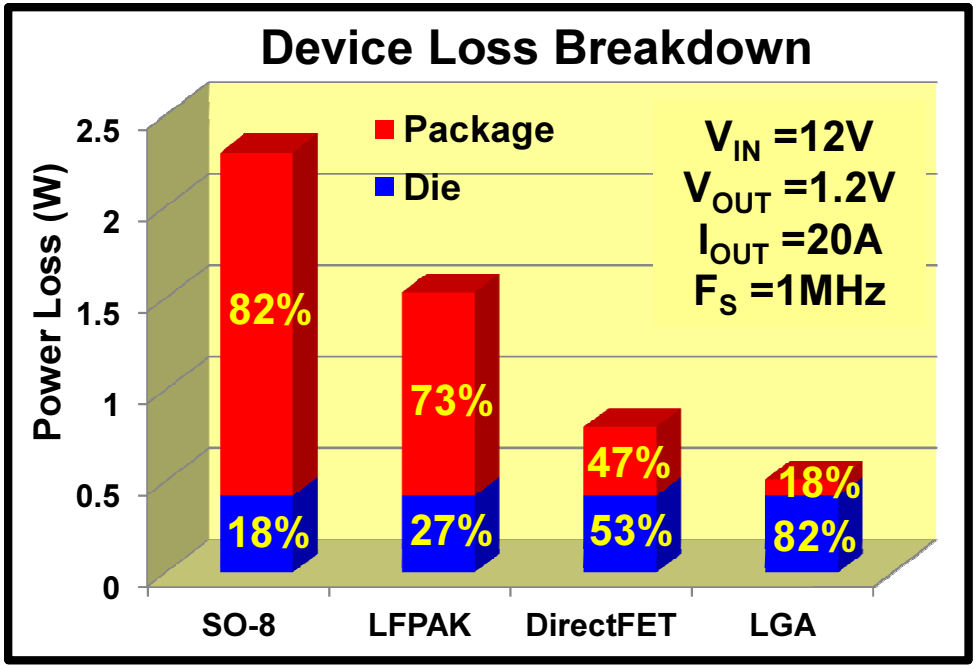


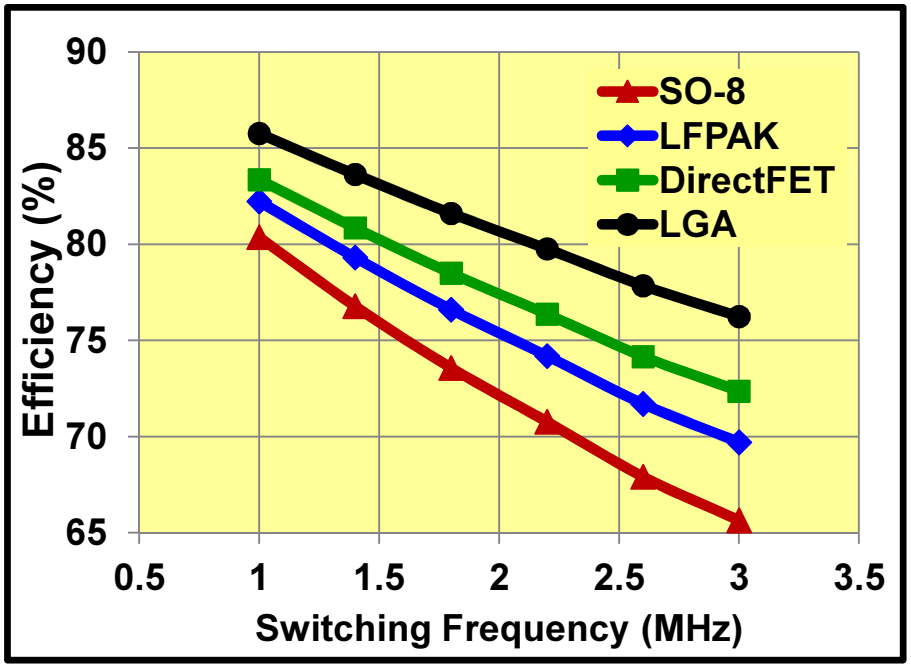
$$P_{T_{CR}} \alpha \frac{V_{IN} * I_{ON} * Q_{GS2}}{2 * I_G}$$

$$P_{T_{VF}} \alpha \frac{V_{IN} * I_{ON} * Q_{GD}}{2 * I_G}$$

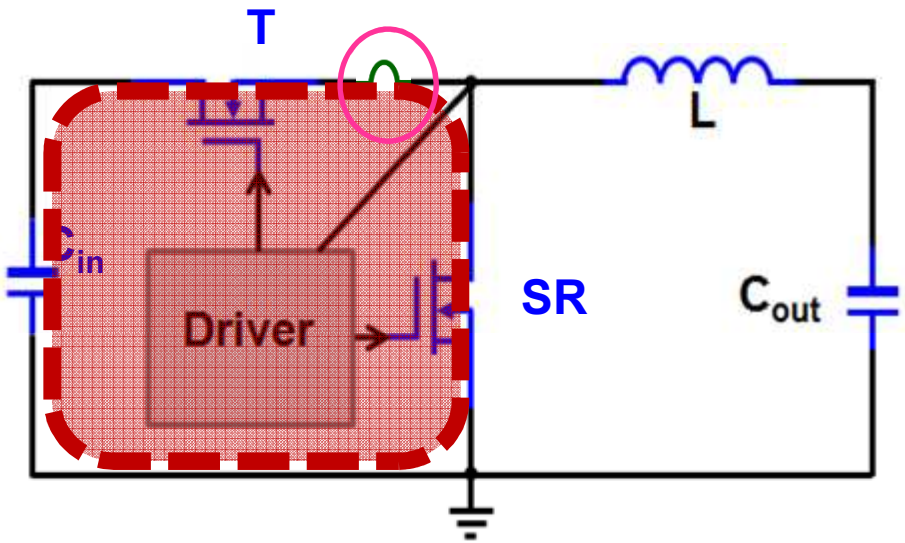
Packaging Evolution





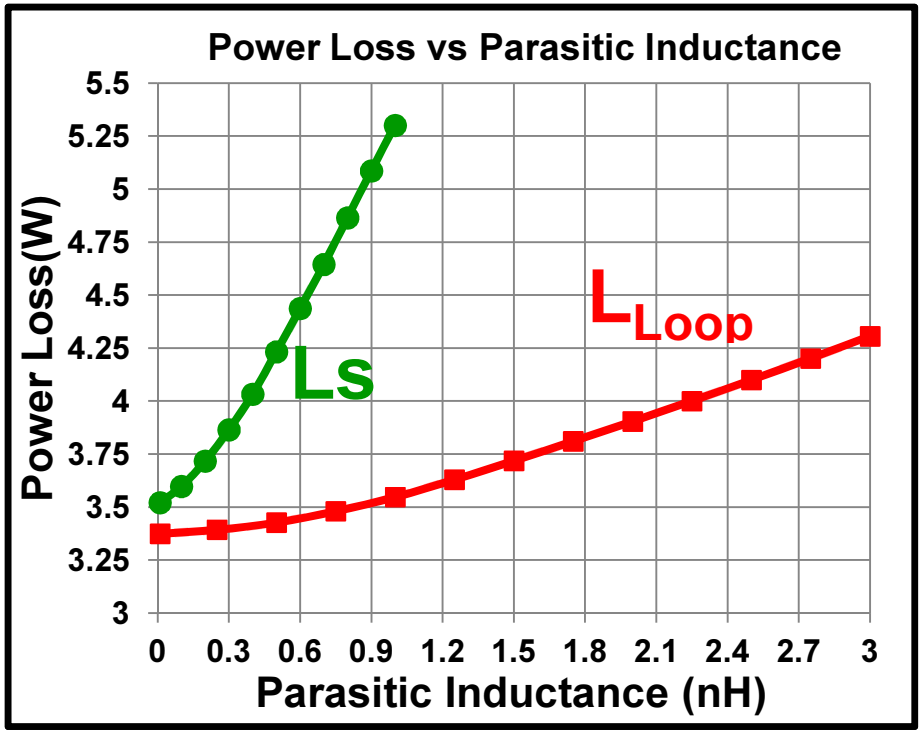


Converter Parasitics



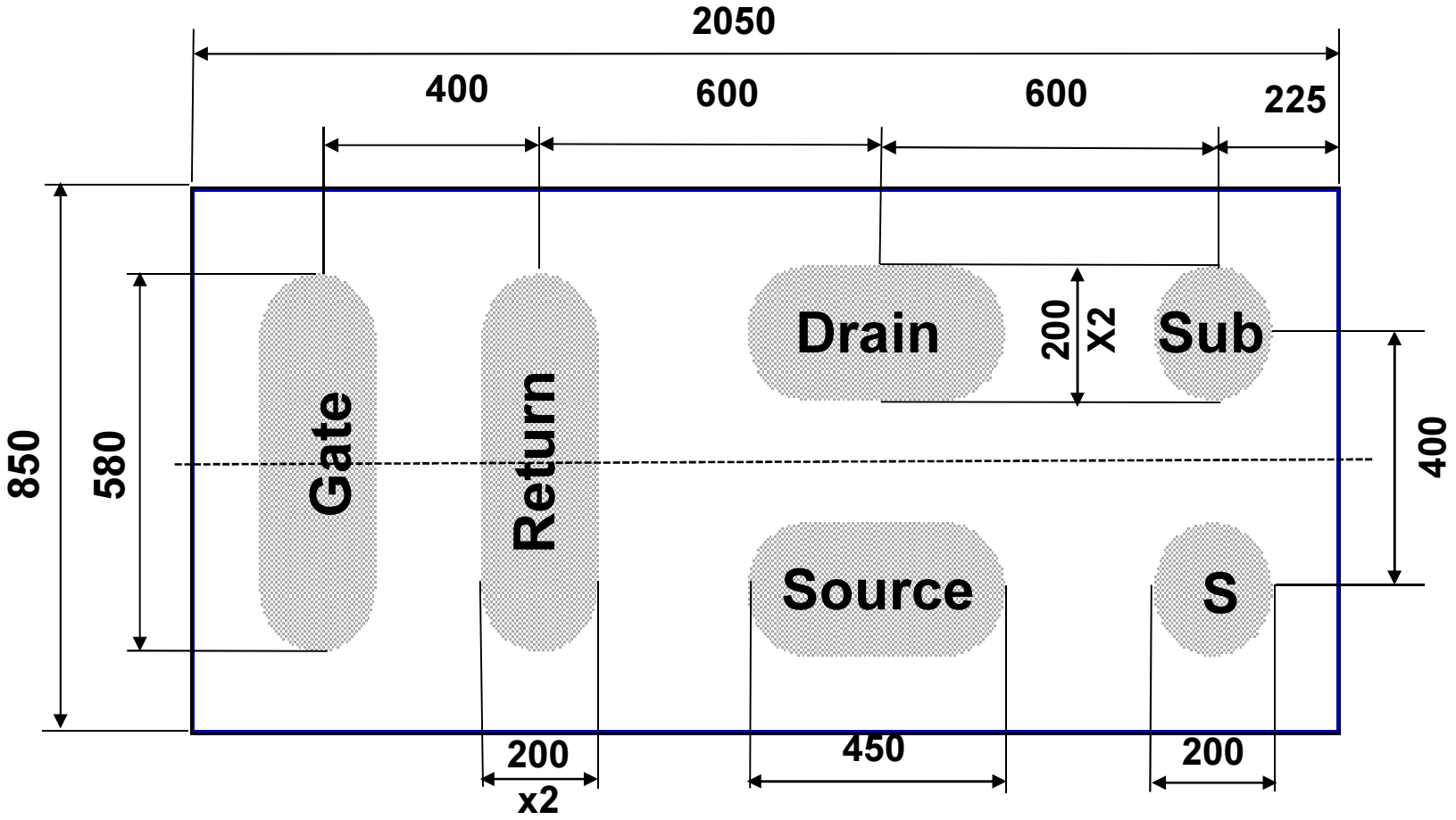
L_S: Common Source Inductance

L_{Loop}: High Frequency Power Loop Inductance



V_{IN}=12 V, V_{OUT}=1.2 V,
f_{sw}=1 MHz, I_{OUT}= 20 A

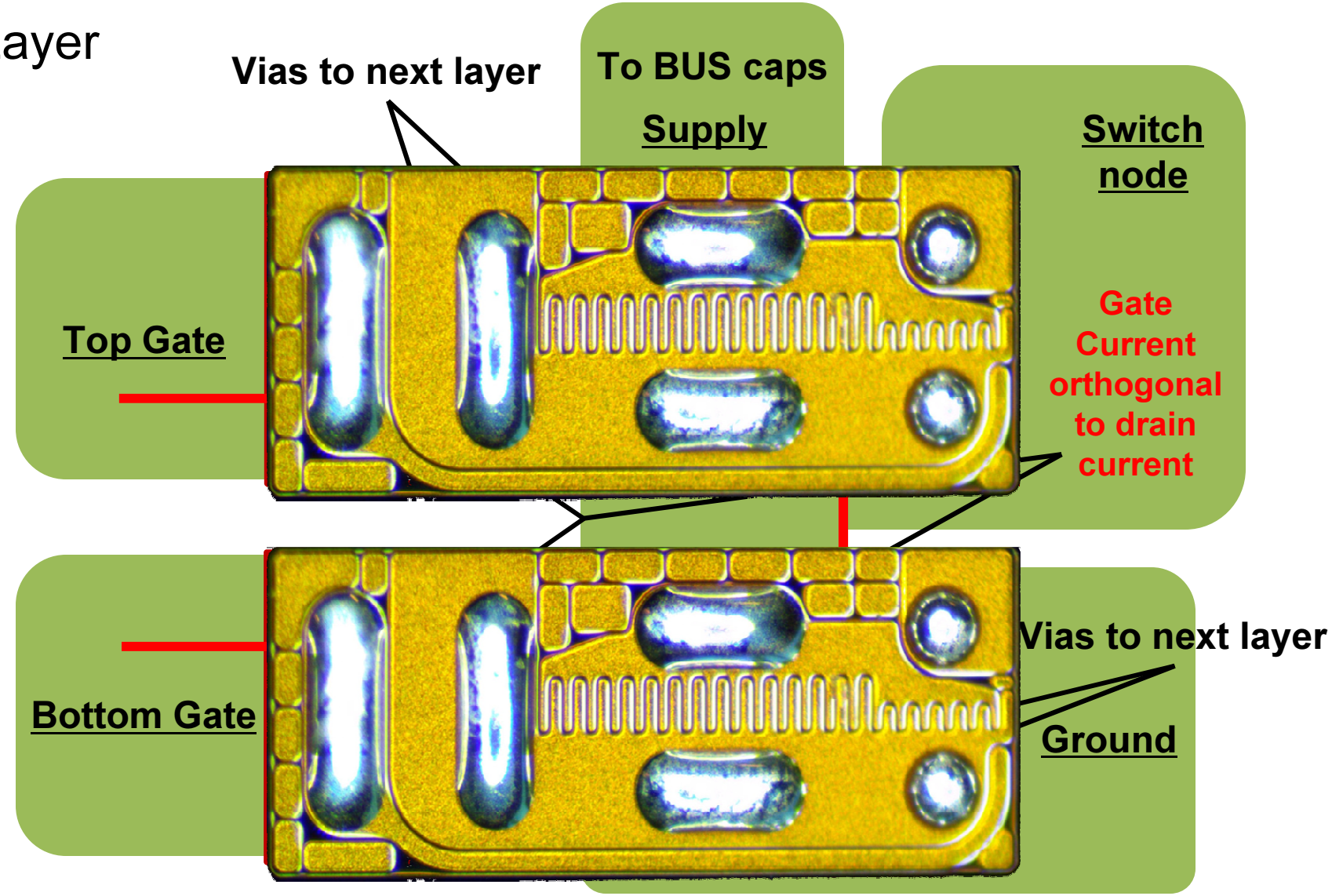
EPC8XXX Package



All dimensions in μm

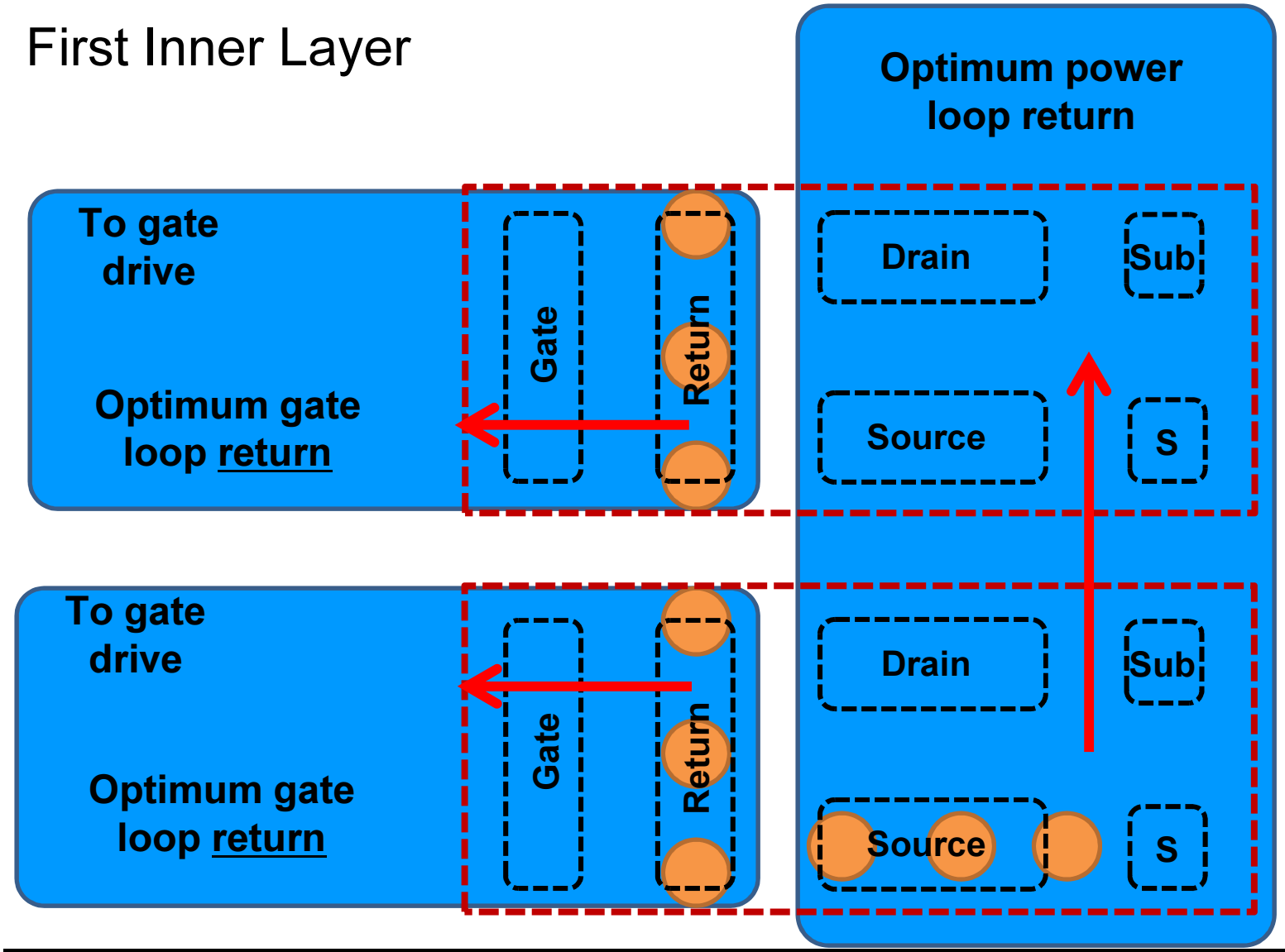
Low Parasitic Layout

Top Layer



Low Parasitic Layout

First Inner Layer

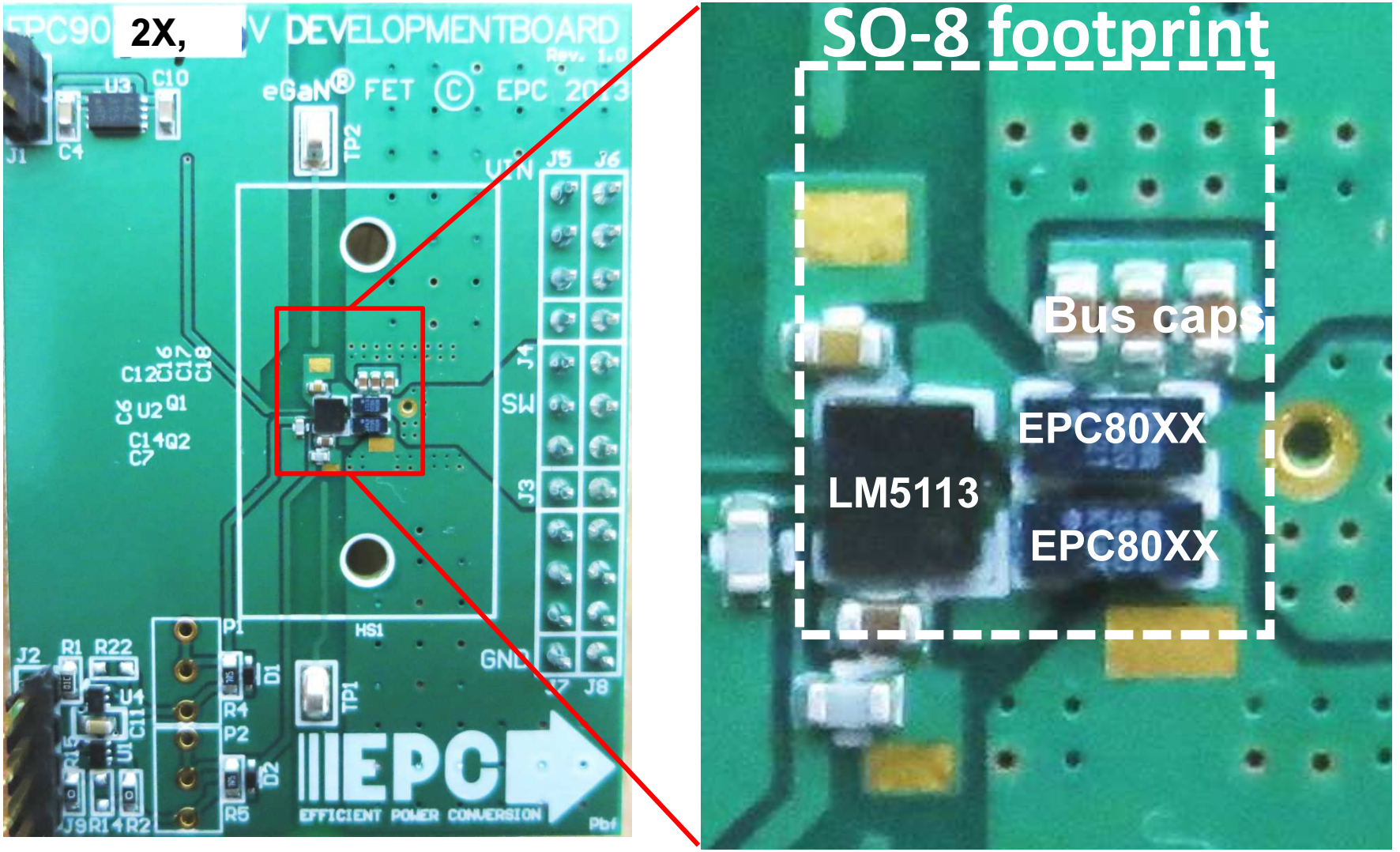


EPC8000 Series Improvements

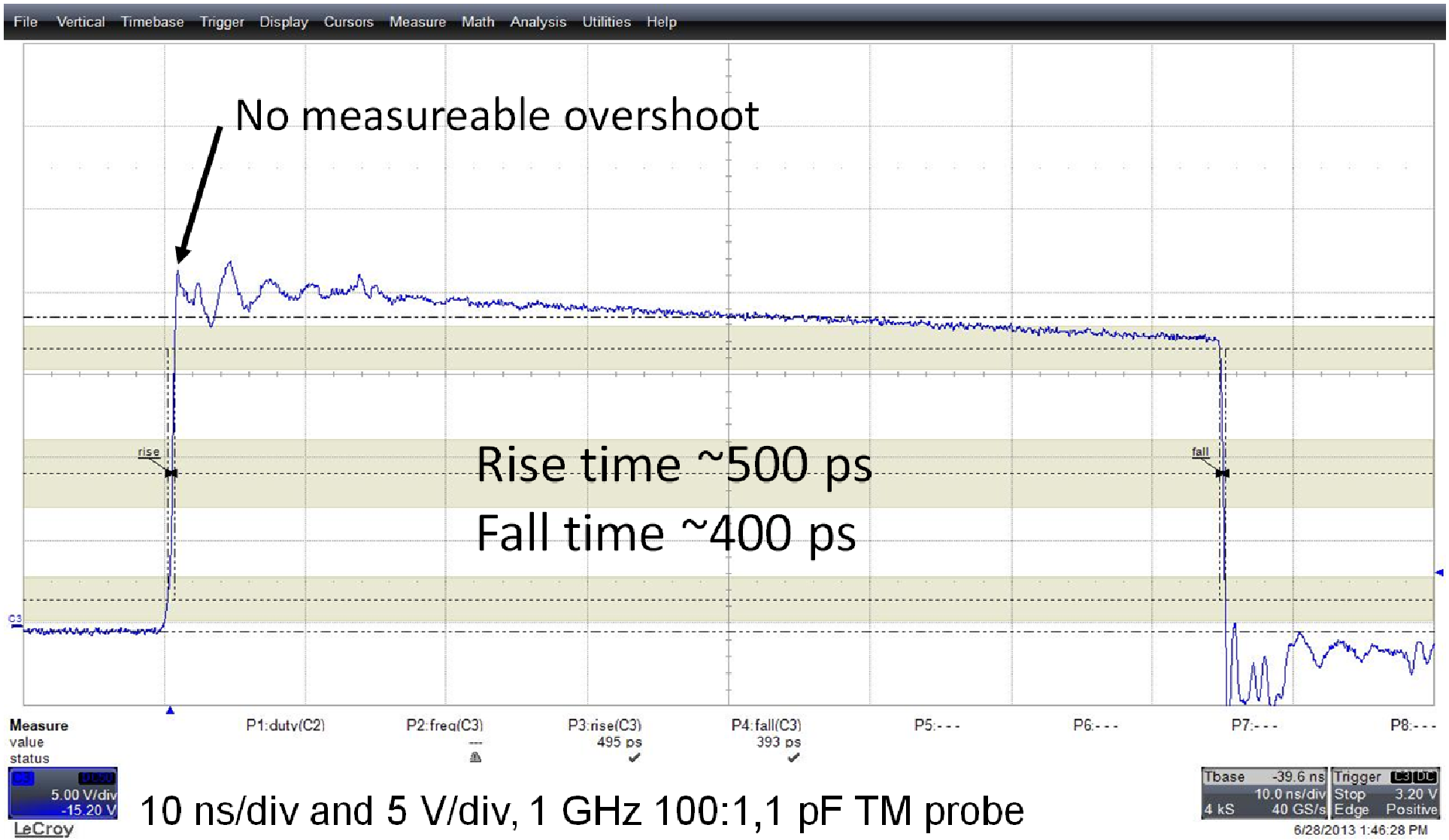
- Reduce active area for lower power / higher frequency operation
- Minimize Hard Switching Figure of Merit
- Complete dv/dt turn-on immunity
- Separate gate and power loops
- Minimize power loop inductance
- Minimize gate loop inductance

Experimental Results

ET Prototype Board

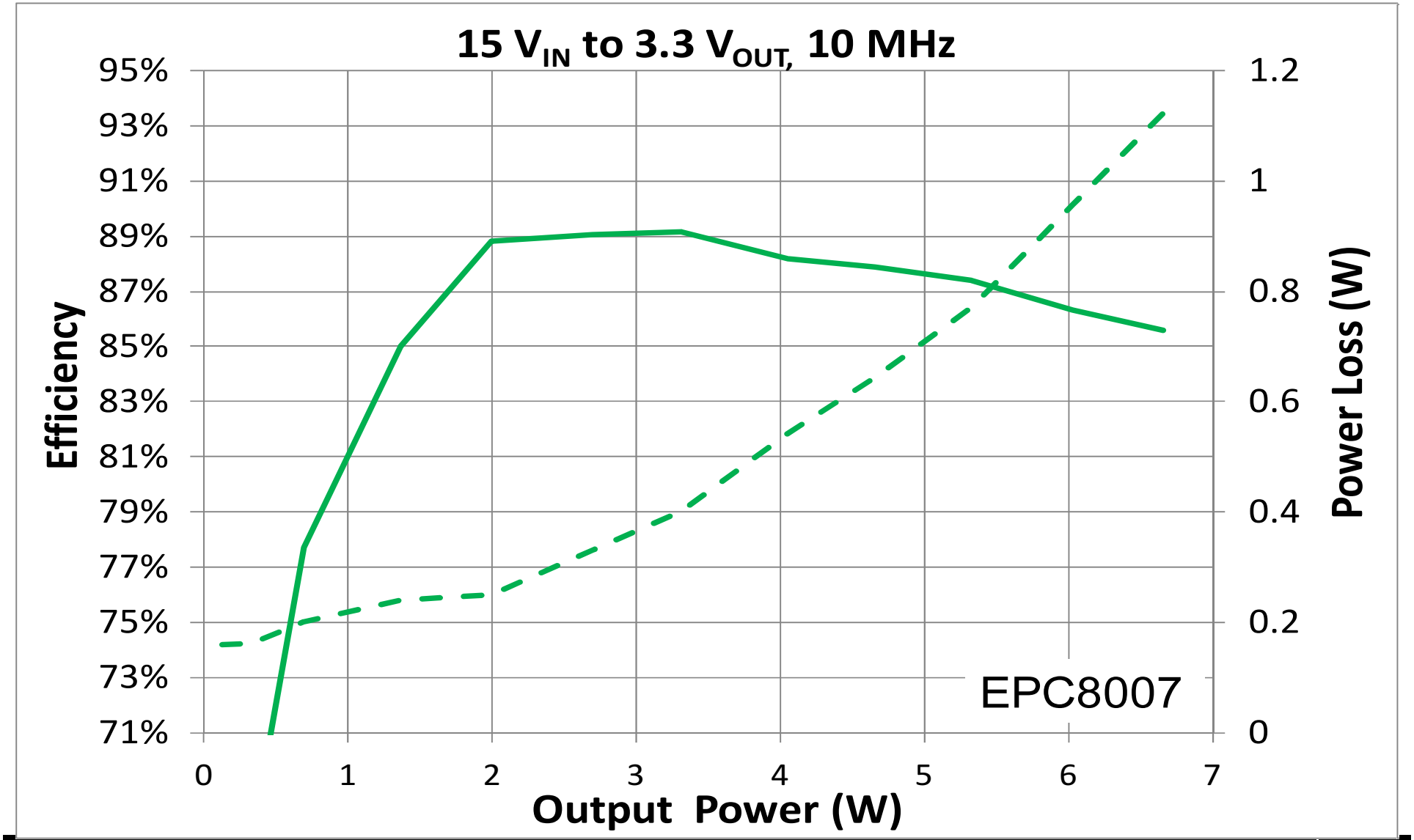


20 V_{BUS}, 10 MHz, 4 A Switching

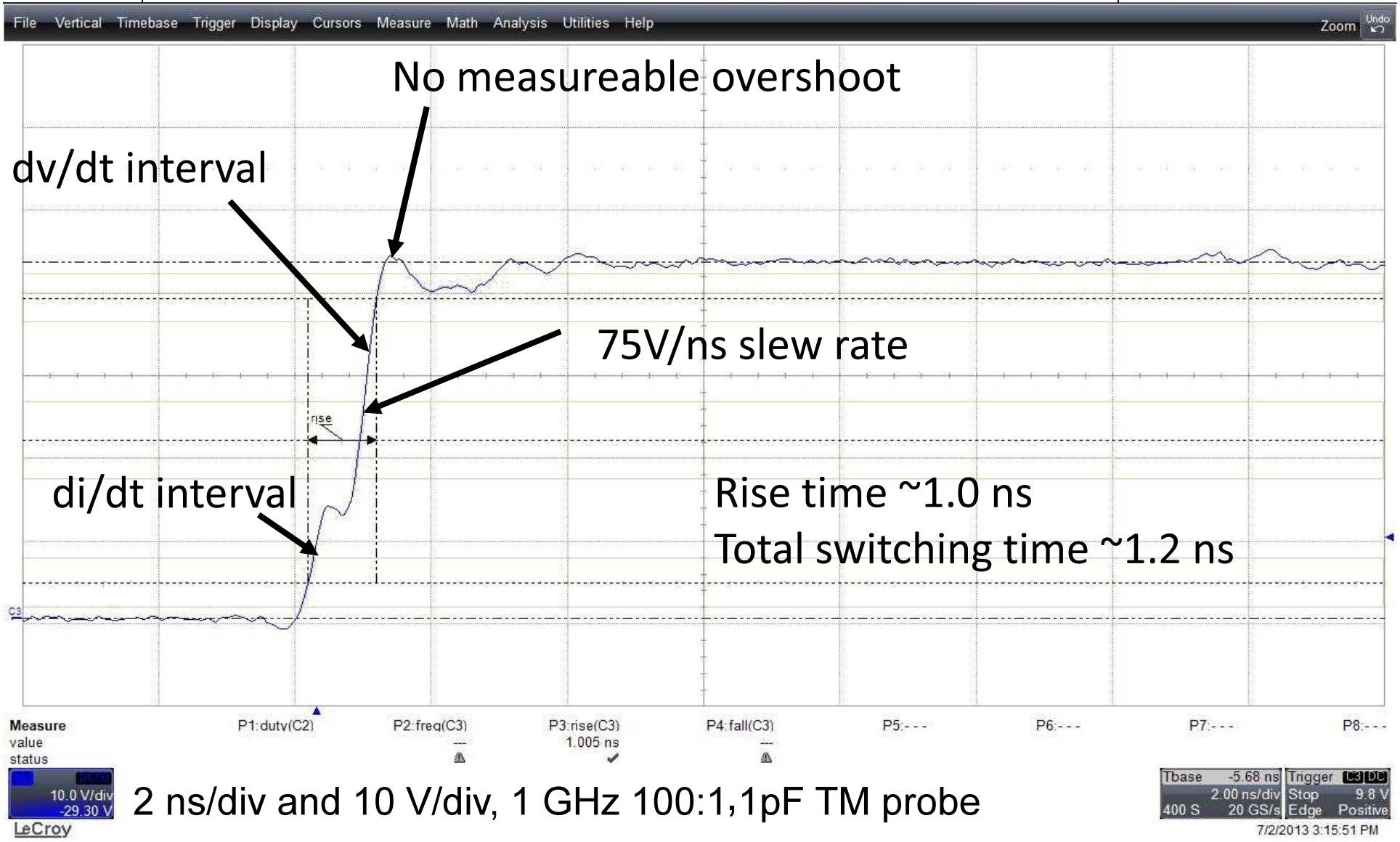


10 ns/div and 5 V/div, 1 GHz 100:1,1 pF TM probe

Near 90% @ >4:1 step down ratio

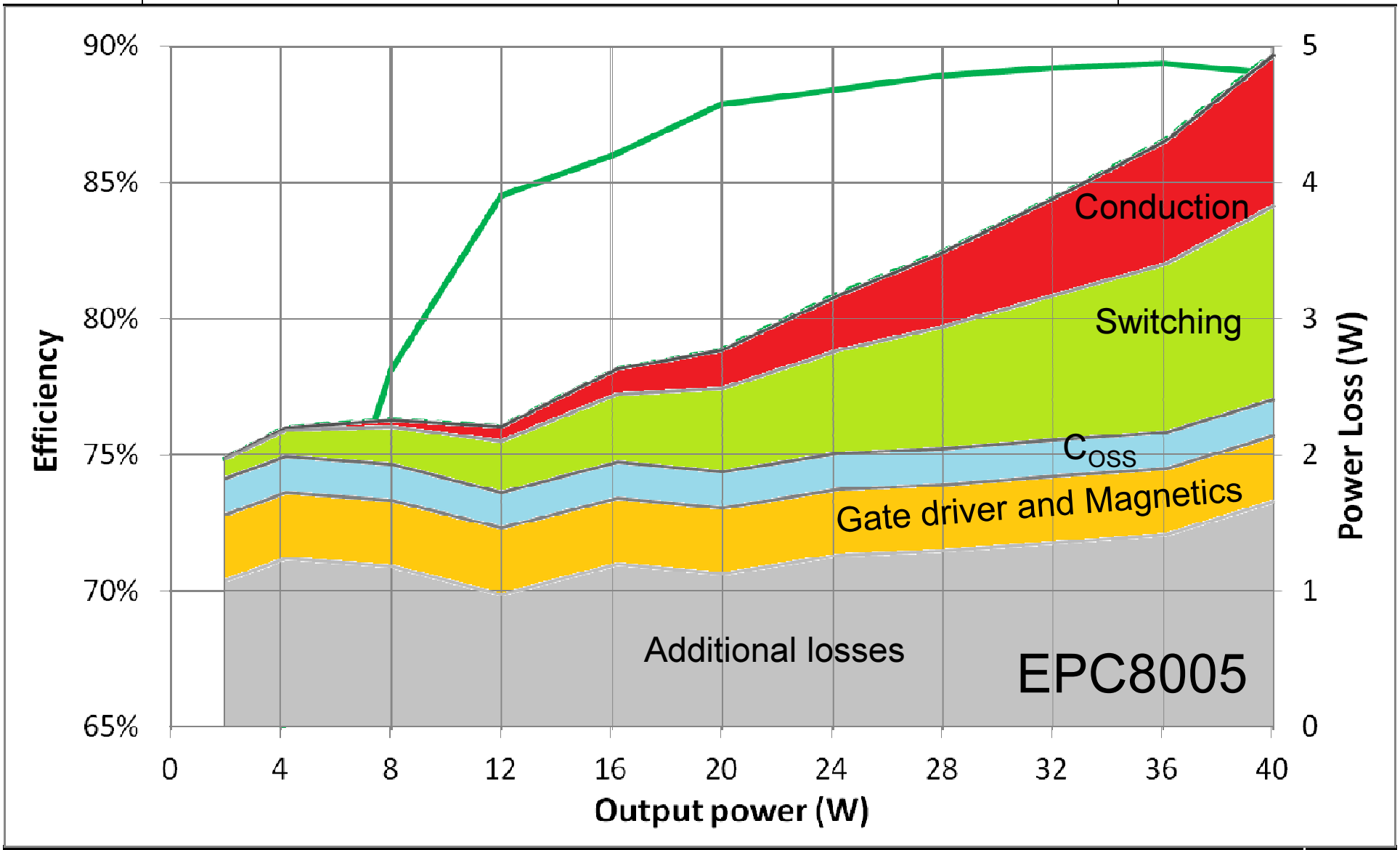


42 V_{IN} at 1 A_{OUT}



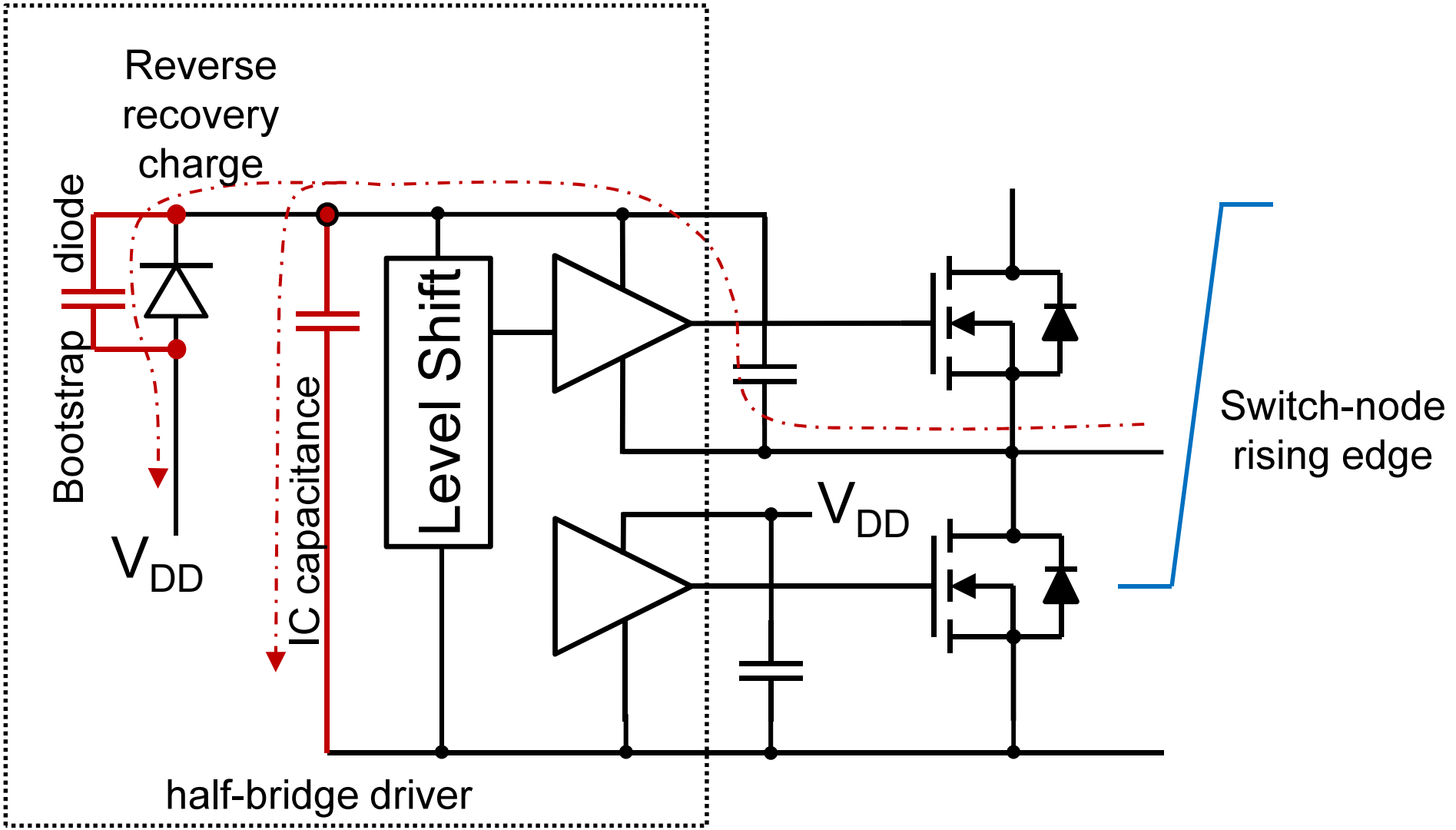
2 ns/div and 10 V/div, 1 GHz 100:1,1pF TM probe

42 V_{IN}, 20 V_{OUT}, 10 MHz

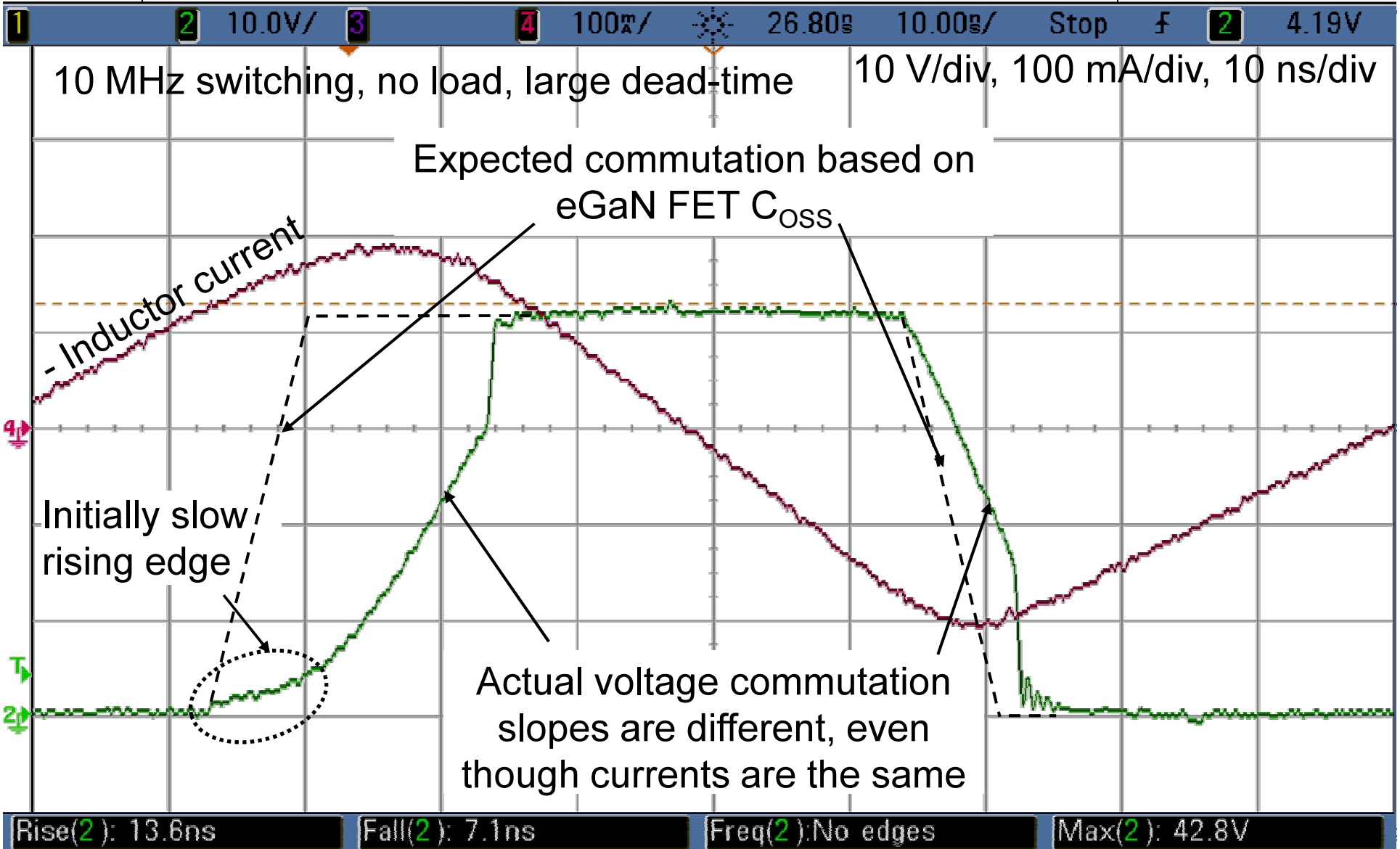


Current Limitations

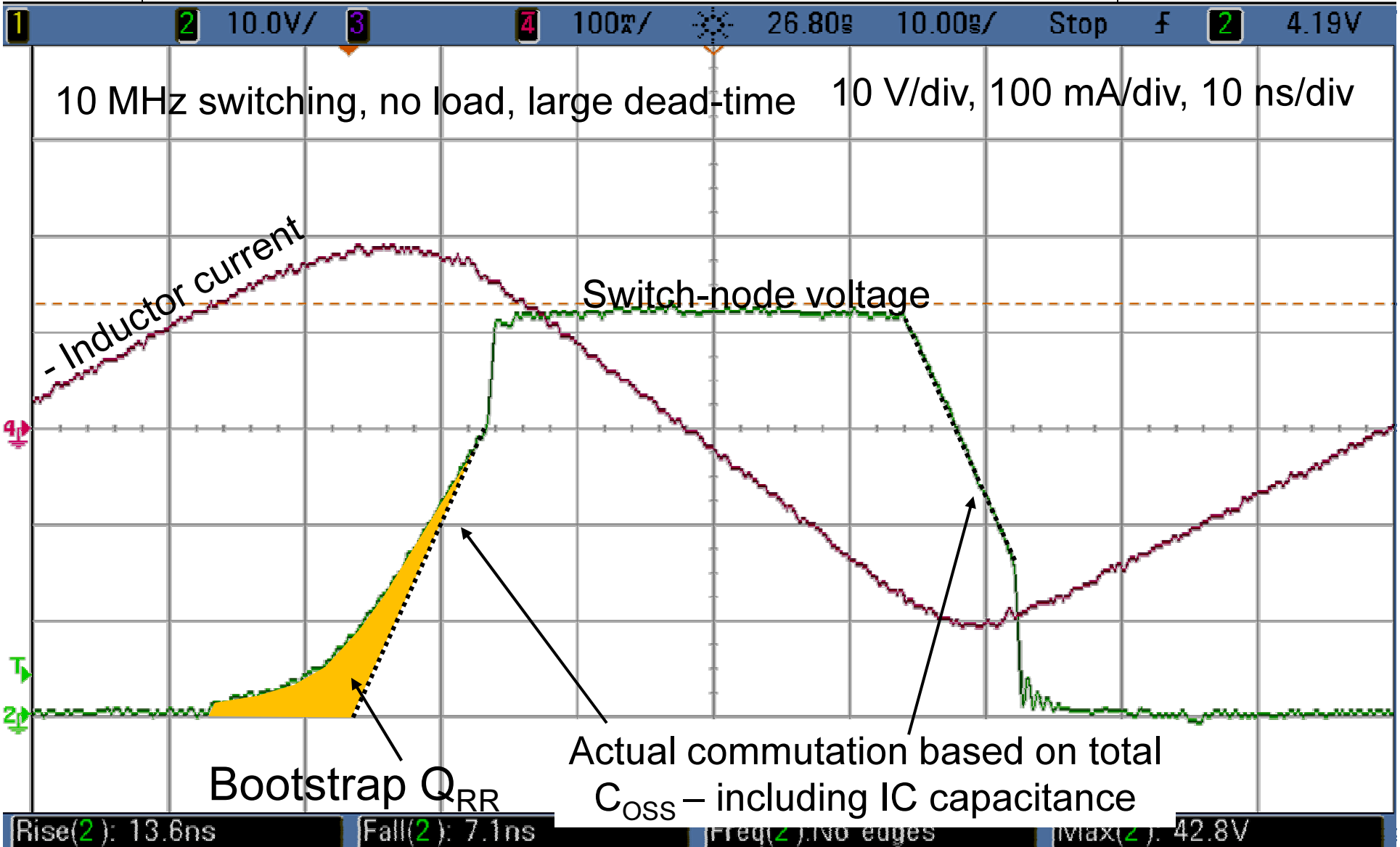
Parasitic Losses



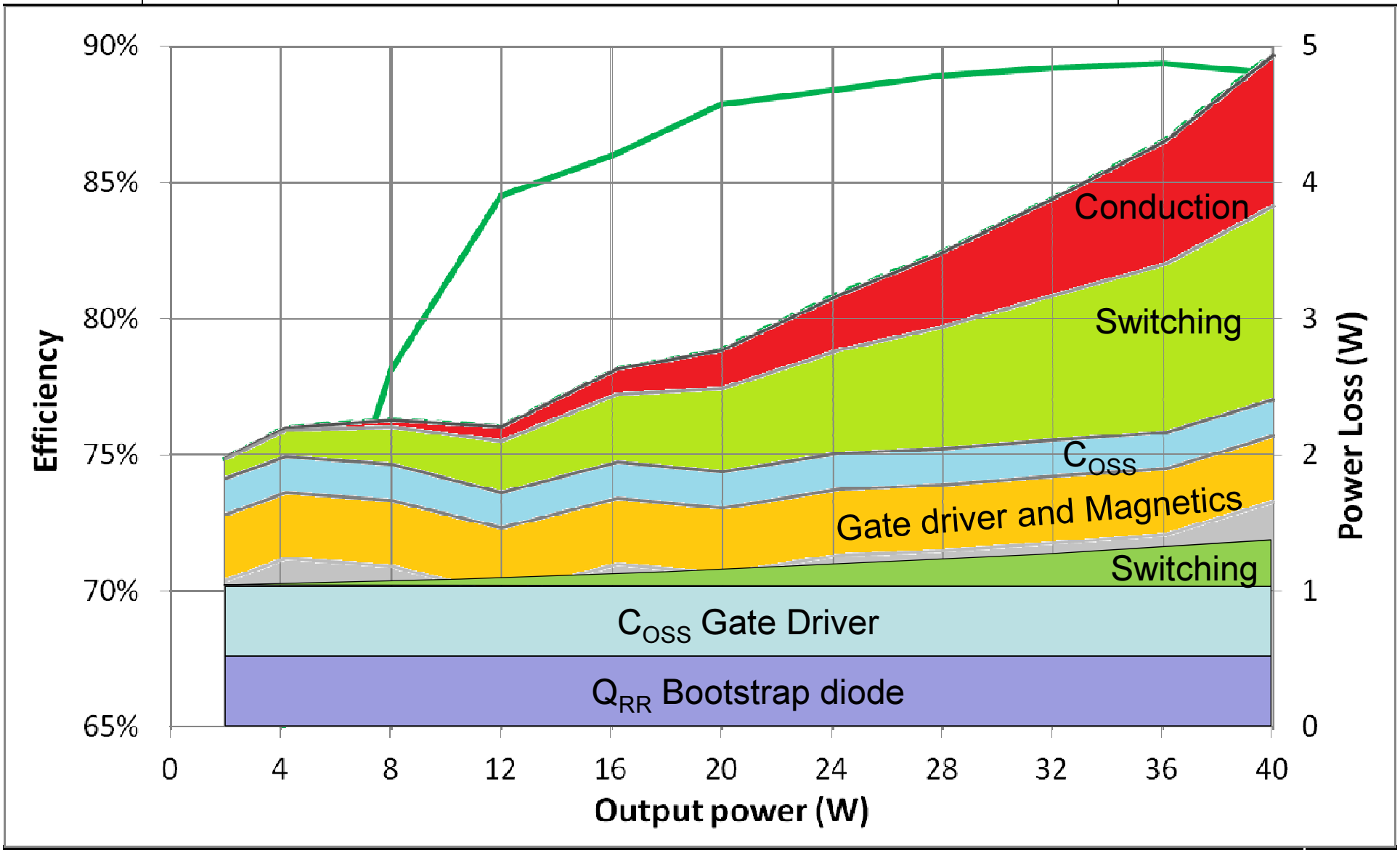
No-load Switching



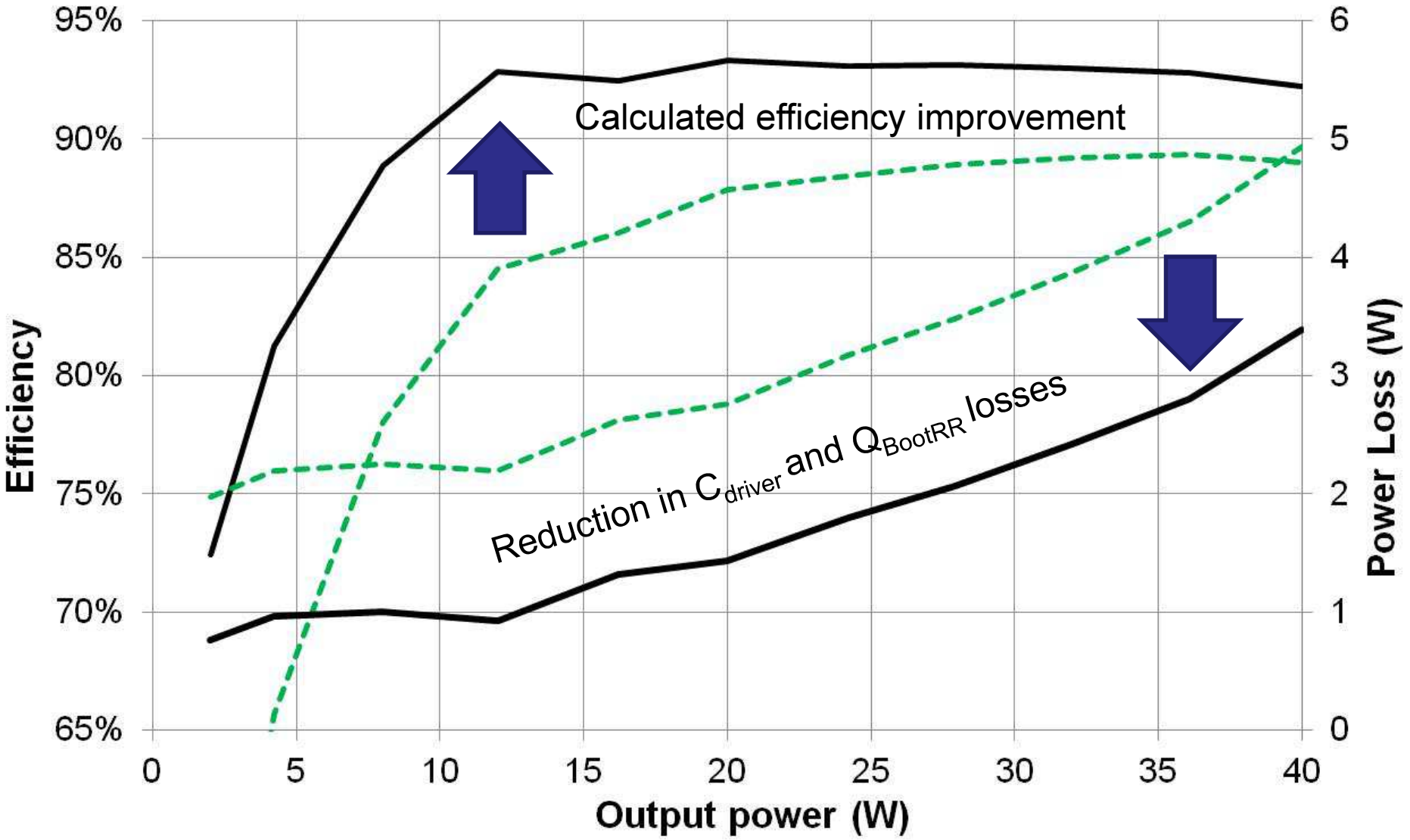
Loss Breakdown



42 V_{IN}, 20 V_{OUT}, 10 MHz



eGaN FET Limited Efficiency



Summary

- New devices enable higher switching frequencies
- Switching 42 V, 40 W at 10 MHz at 89% possible.
- Driver parasitics limit performance – light load losses can be cut in half, and full load losses can be reduced by 25%

Thank you!

Questions?

EPC
EFFICIENT POWER CONVERSION

The end of the road for silicon…..

is the beginning of the eGaN FET journey!